DOCUMENT CHANGE REQUEST

DCR number 1699
Changes required for: General
Originator: Steve Jeffery
Date: 2025/01/28
Date sent: 2024/10/22
Organisation: ESCC Executive
Status: IMPLEMENTED

Title:	INTEGRATED CIRCUITS, SILICON MONOLITHIC, CMOS DIGITAL, MEMORY, RADIATION		
Number:	9304/010	Issue:	3

Other documents affected:

Page:

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Paragraph:

New Para. 2.1.1.2, Deviations from Qualification and Periodic Tests - Chart F4A

Original wording:

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Proposed wording:

See the attached MSWord file ESCC9304010iss4 Draft A for DCR review.

Justification:

Technically acceptable; STMicroelectronics have advised that the bond strength sampling changes have already been discussed with ESA and CNES.

N.B.: this DCR has been raised by the ESCC T.W. following a request to do so from STMicroelectronics Pauline Le Paih.

Attachments:

escc9304010iss4_draft_a_for_dcr_review.docx

Modifications:

- Para. 2.1.1.2(a): Quantity of leads tested is corrected to "15".
- Para. 2.1.1.2(b): Para. is re-worded for clarification and to delete erroneous "applicable to Variant ##".
- New Deviation against Moisture Resistance (applicable to Variant 01 only) is added.

Approval signature:

Date signed: